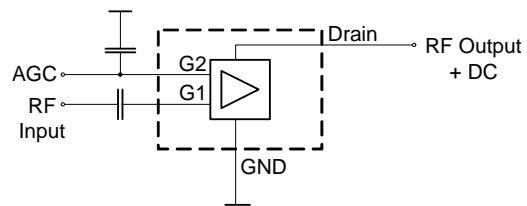
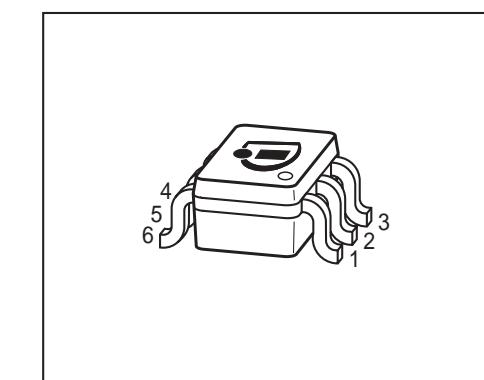
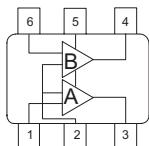


DUAL N-Channel MOSFET Tetrode

- Low noise gain controlled input stages of UHF- and VHF-tuners with 5V supply voltage
- Two AGC amplifiers in one single package
- Integrated stabilized bias network
- Integrated gate protection diodes
- High gain, low noise figure
- Improved cross modulation at gain reduction
- High AGC-range
- Pb-free (RoHS compliant) package
- Qualified according AEC Q101


BG3230


ESD (Electrostatic discharge) sensitive device, observe handling precaution!

| Type | Package | Pin Configuration | | | | | | Marking |
|--------|---------|-------------------|------|------|-------|-----|--------|---------|
| BG3230 | SOT363 | 1=G1* | 2=G2 | 3=D* | 4=D** | 5=S | 6=G1** | KBs |

* For amp. A; ** for amp. B

180° rotated tape loading orientation available

Maximum Ratings

| Parameter | Symbol | Value | Unit |
|-------------------------------|------------------|-------------|------|
| Drain-source voltage | V_{DS} | 8 | V |
| Continuous drain current | I_D | 25 | mA |
| Gate 1/ gate 2-source current | $\pm I_{G1/2SM}$ | 1 | |
| Gate 1/ gate 2-source voltage | $\pm V_{G1/G2S}$ | 6 | V |
| Total power dissipation | P_{tot} | 200 | mW |
| Storage temperature | T_{stg} | -55 ... 150 | °C |
| Channel temperature | T_{ch} | 150 | |

Thermal Resistance

| Parameter | Symbol | Value | Unit |
|---|-------------|------------|------|
| Channel - soldering point ¹⁾ | R_{thchs} | ≤ 280 | K/W |

Electrical Characteristics at $T_A = 25^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Values | | | Unit |
|-----------|--------|--------|------|------|------|
| | | min. | typ. | max. | |

DC Characteristics

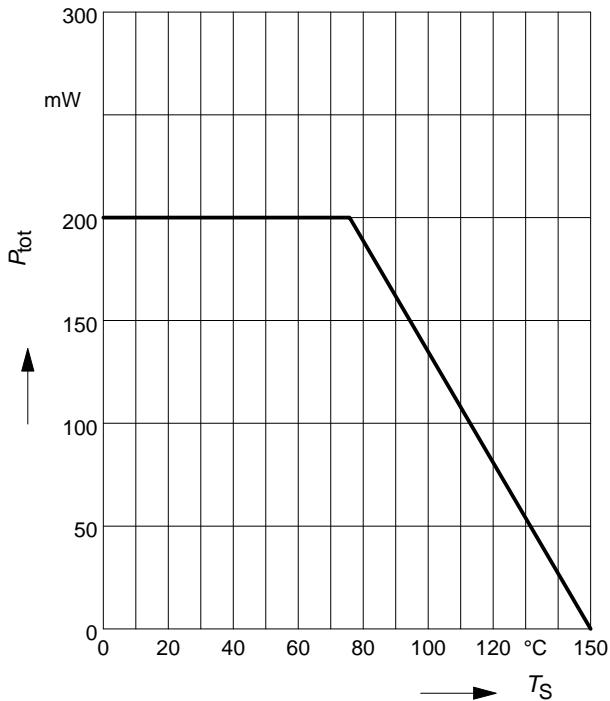
| | | | | | |
|--|--------------------|----|----|-----|---------------|
| Drain-source breakdown voltage $I_D = 100 \mu\text{A}, V_{G1S} = 0, V_{G2S} = 0$ | $V_{(BR)DS}$ | 12 | - | - | V |
| Gate1-source breakdown voltage $+I_{G1S} = 10 \text{ mA}, V_{G2S} = 0, V_{DS} = 0$ | $+V_{(BR)G1SS}$ | 6 | - | 15 | |
| Gate2 source breakdown voltage $\pm I_{G2S} = 10 \text{ mA}, V_{G1S} = 0, V_{DS} = 0$ | $\pm V_{(BR)G2SS}$ | 6 | - | 15 | |
| Gate1-source leakage current $V_{G1S} = 6 \text{ V}, V_{G2S} = 0$ | $+I_{G1SS}$ | - | - | 50 | μA |
| Gate 2 source leakage current $\pm V_{G2S} = 6 \text{ V}, V_{G1S} = 0, V_{DS} = 0$ | $\pm I_{G2SS}$ | - | - | 50 | nA |
| Drain current $V_{DS} = 5 \text{ V}, V_{G1S} = 0, V_{G2S} = 4 \text{ V}$ | I_{DSS} | - | - | 100 | μA |
| Operating current (selfbiased) $V_{DS} = 5 \text{ V}, V_{G2S} = 4 \text{ V}$ | I_{DSO} | - | 13 | - | mA |
| Gate2-source pinch-off voltage $V_{DS} = 5 \text{ V}, I_D = 100 \mu\text{A}$ | $V_{G2S(p)}$ | - | 1 | - | V |

¹⁾For calculation of R_{thJA} please refer to Application Note Thermal Resistance

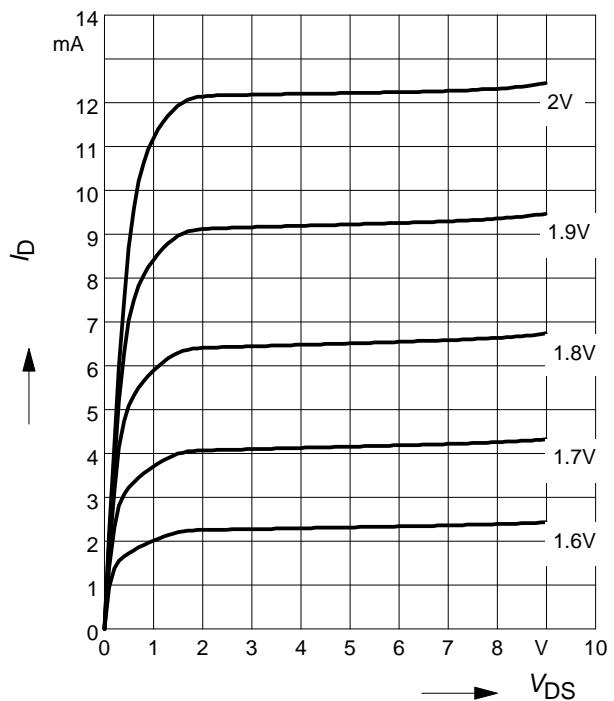
Electrical Characteristics at $T_A = 25^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Values | | | Unit |
|---|--------------|--------|------|------|------|
| | | min. | typ. | max. | |
| AC Characteristics - (verified by random sampling) | | | | | |
| Forward transconductance $V_{DS} = 5 \text{ V}, V_{G2S} = 4 \text{ V}$ | g_{fs} | - | 33 | - | mS |
| Gate1 input capacitance $V_{DS} = 5 \text{ V}, V_{G2S} = 4 \text{ V}, f = 10 \text{ MHz}$ | C_{g1ss} | - | 1.9 | - | pF |
| Output capacitance $V_{DS} = 5 \text{ V}, V_{G2S} = 4 \text{ V}, f = 10 \text{ MHz}$ | C_{dss} | - | 1.1 | - | |
| Power gain (self biased) $V_{DS} = 5 \text{ V}, V_{G2S} = 4 \text{ V}, f = 800 \text{ MHz}$ $V_{DS} = 5 \text{ V}, V_{G2S} = 4 \text{ V}, f = 45 \text{ MHz}$ | G_p | - | 24 | - | dB |
| Noise figure (self biased) $V_{DS} = 5 \text{ V}, V_{G2S} = 4 \text{ V}, f = 800 \text{ MHz}$ $V_{DS} = 5 \text{ V}, V_{G2S} = 4 \text{ V}, f = 45 \text{ MHz}$ | F | - | 1.3 | - | dB |
| Gain control range $V_{DS} = 5 \text{ V}, V_{G2S} = 4\dots0 \text{ V}, f = 800 \text{ MHz}$ | ΔG_p | 45 | - | - | |
| Cross-modulation $k=1\%$, $f_w=50\text{MHz}$, $f_{unw}=60\text{MHz}$ AGC = 0 dB AGC = 10 dB AGC = 40 dB | X_{mod} | 90 | - | - | - |
| | | - | 87 | - | |
| | | 96 | 100 | - | |

Total power dissipation $P_{\text{tot}} = f(T_S)$



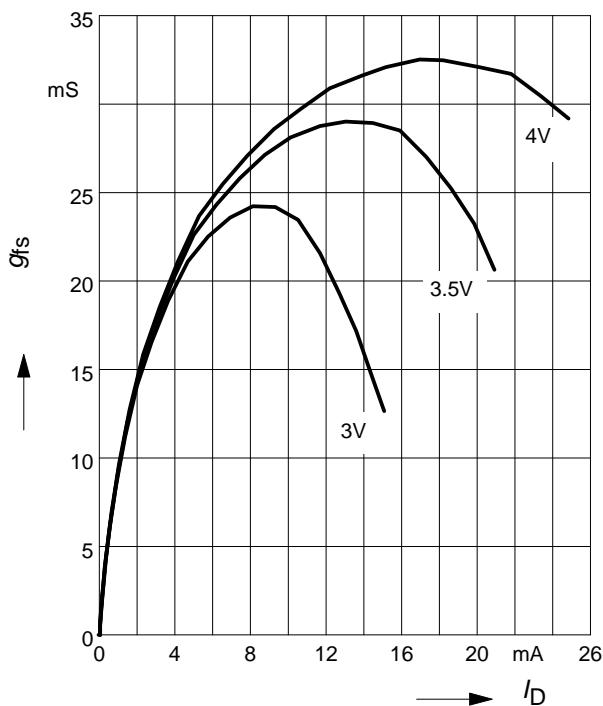
Output characteristics $I_D = f(V_{DS})$



Gate 1 forward transconductance

$$g_{fs} = f(I_D)$$

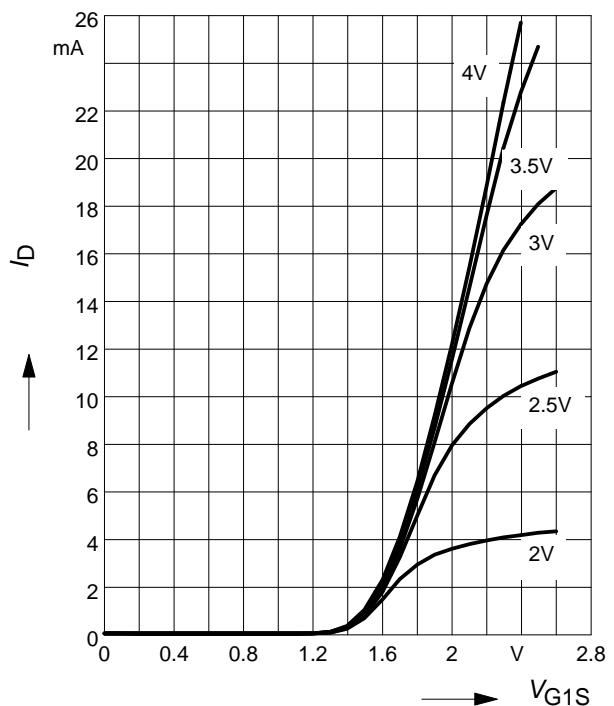
$V_{DS} = 5V$, V_{G2S} = Parameter



Drain current $I_D = f(V_{G1S})$

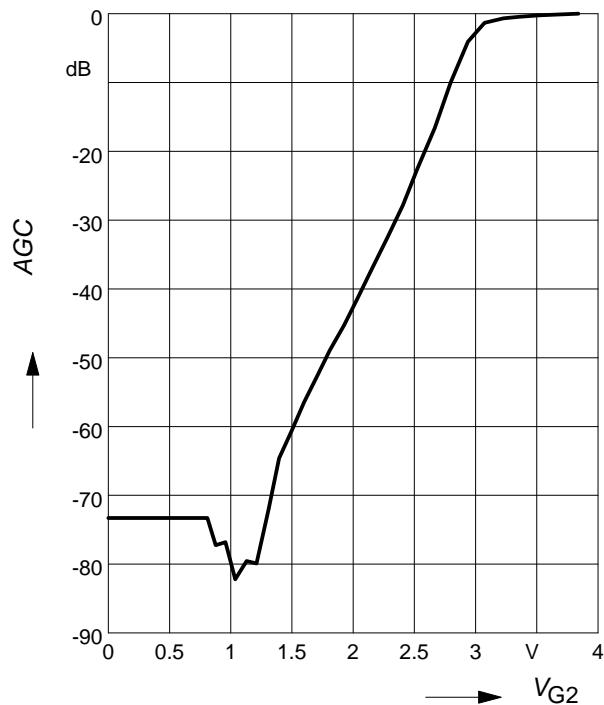
$$V_{DS} = 5V$$

V_{G2S} = Parameter



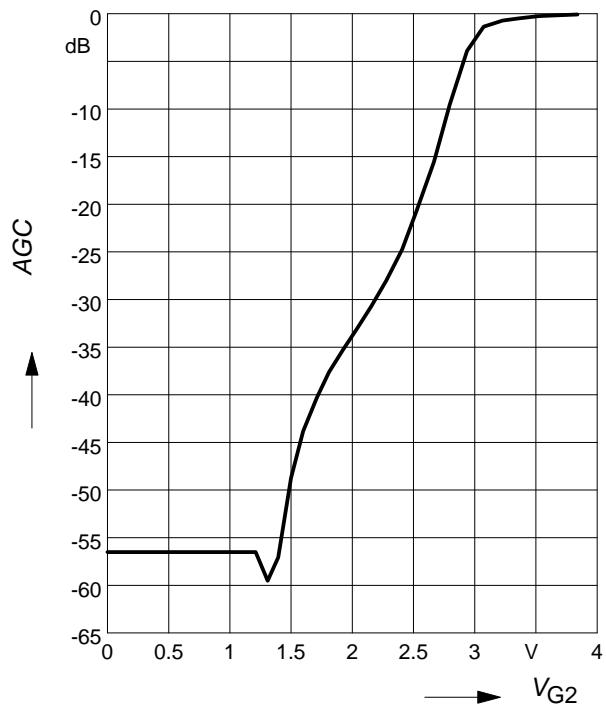
AGC characteristic $AGC = f(V_{G2S})$

$f = 200 \text{ MHz}$



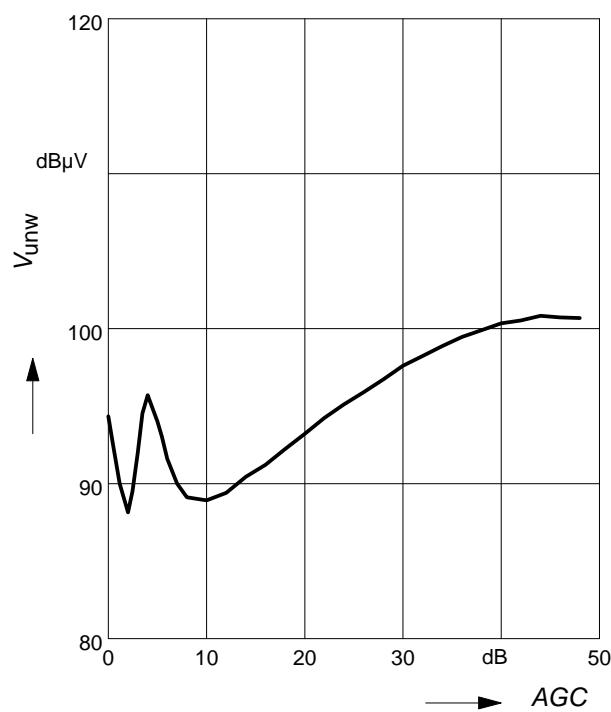
AGC characteristic $AGC = f(V_{G2S})$

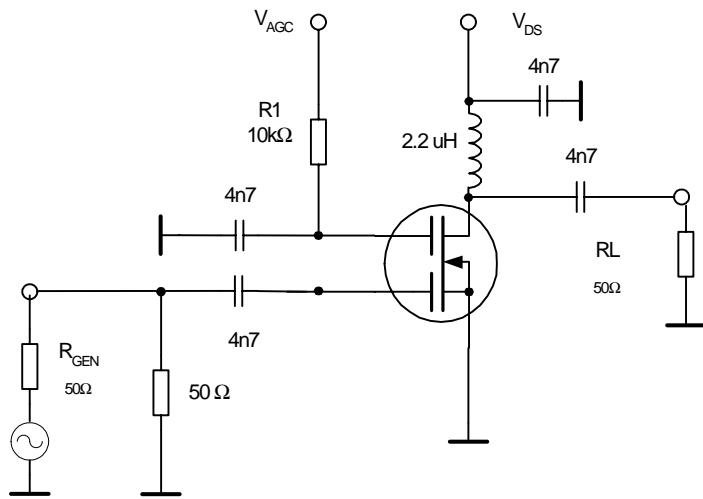
$f = 800 \text{ MHz}$



Crossmodulation $V_{unw} = (AGC)$

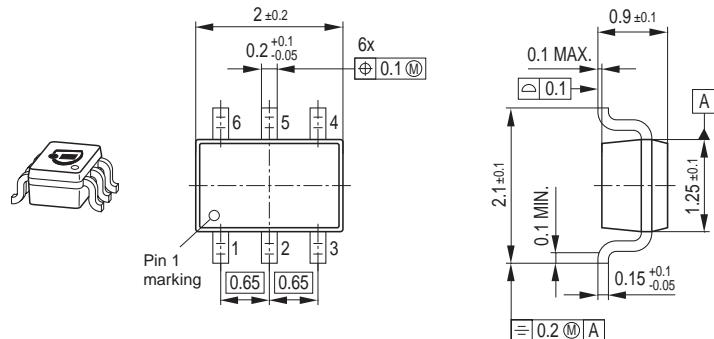
$V_{DS} = 5 \text{ V}$, $R_{g1} = 68 \text{ k}\Omega$



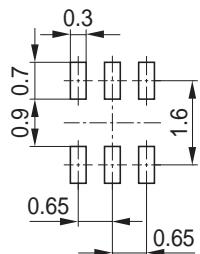
Crossmodulation test circuit


fullbiased

Package Outline

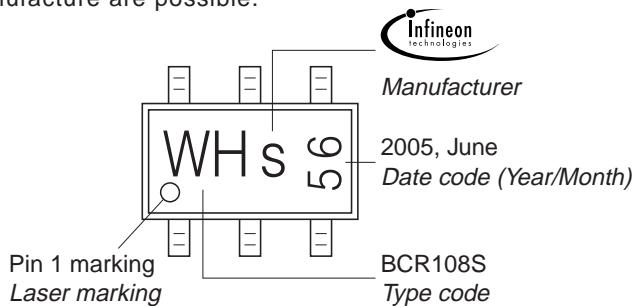


Foot Print



Marking Layout (Example)

Small variations in positioning of Date code, Type code and Manufacture are possible.

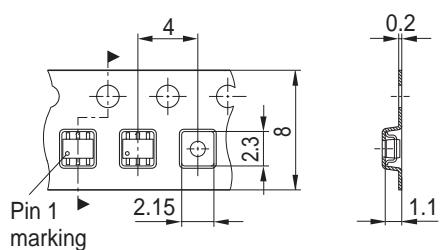


Standard Packing

Reel ø180 mm = 3.000 Pieces/Reel

Reel ø330 mm = 10.000 Pieces/Reel

For symmetric types no defined Pin 1 orientation in reel.



Edition 2006-02-01

Published by

Infineon Technologies AG

81726 München, Germany

© Infineon Technologies AG 2007.

All Rights Reserved.

Attention please!

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie"). With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office (www.infineon.com).

Warnings

Due to technical requirements components may contain dangerous substances.

For information on the types in question please contact your nearest Infineon Technologies Office.

Infineon Technologies Components may only be used in life-support devices or systems with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system.

Life support devices or systems are intended to be implanted in the human body, or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.